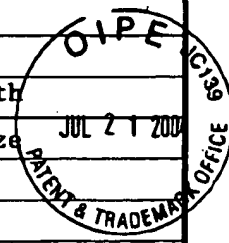


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INFORMATION DISCLOSURE STATEMENT BY APPLICANT (Use as many sheets as necessary)		Application Number	10/720,763
		Filing Date	Even Date Herewith
		First Named Inventor	Nikolay I. Agladze
		Art Unit	2877
		Examiner Name	Samuel A. Turner
Sheet 1 of 1	Attorney Docket Number	CRF D-3094/US	



NON PATENT LITERATURE DOCUMENTS			
Examiner Initials*	Cite No. ¹	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T ²
SAT	1	"Digital array scanned interferometer: sensors and results," Wm Hayden Smith and Philip D. Hammer; Applied Optics, Vol. 35, No. 16, June 1996	
↑	2	"Photographic Method of Recording in Fourier Spectrometry," I.P. Petrov and B.N. Grechushnikov; Optics and Spectroscopy, 19, p. 82-83 (1965)	
	3	"Computational Aberration Correction for an Arbitrary Linear Imaging System," L. J. Allen, M. P. Oxley, and D. Paganin; Physical Review Letters, Vol. 87, No. 12, 17 September 2001	
	4	"Effects of aberrations on spatially modulated Fourier transform spectrometers," R. Glenn Sellar, J. Bruce Rafert; Optical Engineering, September 1994, Vol. 33, No. 9/3087	
	5	"Fourier transform spectrometer with a self-scanning photodiode array," Takayuki Okamoto, Satoshi Kawata, and Shigeo Minami; Applied Optics, 15 January 1984, Vol. 23, No. 2	
	6	"Spatially Encoded Fourier Transform Spectroscopy in the Ultraviolet to Near-Infrared," Jonathan V. Sweedler and M. Bonner Denton; Applied Spectroscopy, Vol. 43, No. 8, 1989	
↓	7	"Monolithic Fourier-transform imaging spectrometer," J. Bruce Rafert, R. Glenn Sellar, and Joel H. Blatt; Applied Optics, Vol. 34, No. 31, 1 November 1995	
SAT	8	"Phase Retrieval through Focus Variation for Ultra-Resolution in Field-Emission Transmission Electron Microscopy," Wim Coene and Guido Janssen, Marc Op de Beeck and Dirk Van Dyck; Physical Review Letters, Vol. 69, No. 26, 28 December 1992	

Examiner Signature	S.A. Turner	Date Considered	11-12-04
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Application Number	10/720,763
Filing Date	Even Date Herewith
First Named Inventor	Nikolay I. Agladze
Group Art Unit	2877
Examiner Name	Samuel A. Turner
Attorney Docket Number	CRF D-3094/US

U.S. PATENT DOCUMENTS

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S.A. TUNGA

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